

Accepted Manuscript

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PII: S0040-6090(15)00840-8
DOI: doi: [10.1016/j.tsf.2015.09.005](https://doi.org/10.1016/j.tsf.2015.09.005)
Reference: TSF 34614

To appear in: *Thin Solid Films*

Received date: 23 January 2015
Revised date: 14 August 2015
Accepted date: 3 September 2015



Please cite this article as: Sanjaya Brahma, P. Jaiswal, K.S. Suresh, Kuang-Yao Lo, Satyam Suwas, S.A. Shivashankar, Effect of substrates and surfactants over the evolution of crystallographic texture of nanostructured ZnO thin films deposited through microwave irradiation, *Thin Solid Films* (2015), doi: [10.1016/j.tsf.2015.09.005](https://doi.org/10.1016/j.tsf.2015.09.005)

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Effect of substrates and surfactants over the evolution of crystallographic texture of nanostructured ZnO thin films deposited through microwave irradiation

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Abstract

In spite of intense research on ZnO over the past decade, the detailed investigation about the crystallographic texture of as obtained ZnO thin films/coatings, and its deviation with growth surface is scarce. We report a systematic study about the orientation distribution of nanostructured ZnO thin films fabricated by microwave irradiation with the variation of substrates and surfactants. The nanostructured films comprising of ZnO nanorods are grown on semiconductor substrates such as [Si(100), Ge(100)], conducting substrates (ITO-coated glass, Cr coated Si), and polymer coated Si (PMMA/Si) to examine the respective development of crystallographic texture. The ZnO deposited on semiconductor substrates yields mixed texture, whereas c-axis oriented ZnO nanostructured films are obtained by conducting substrate, and PMMA coated Si substrates. Among all the surfactants, nanostructured film produced by using the lower molecular weight of polymeric surfactants (polyvinylpyrrolidone) shows a stronger (0002) texture, and that can be tuned to $(10\bar{1}0)$ by increasing the molecular weight of the surfactant. The strongest basal pole is achieved for the ZnO deposited on PMMA coated Si as substrate, and cetyl-trimethyl ammonium bromide

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